

Application  
Number

IDS Flag Clearance for Application 10727239

**IDS  
Information**

Content	Mailroom Date	Entry Number	IDS Review	Last Modified	Reviewer
M844	2003-12-02	18	Y <input checked="" type="checkbox"/>	2006-07-14 17:38:19.0	cbritt
<input type="button" value="Update"/>					

## EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	134082	(memory or (self adj test) or BIST).ab. and interface	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/03/16 09:35
L2	20752	(memory or (self adj test) or BIST).ab. and (((first second) near2 (pass cycle run)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/03/16 09:36
L3	745	(memory or (self adj test) or BIST).ab. and (((first second) near2 (pass cycle run))) with (fail failing failed failure error erroneous bad))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/03/16 09:48
L4	1391	(memory or (self adj test) or BIST).ab. and (((first second) near2 (pass cycle test tester testing tested run))) with (fail failing failed failure error erroneous bad))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/03/16 09:49
L5	636588	(memory or (self adj test) or BIST).ab. and (((first second) near2 (pass cycle test tester testing tested run))) with (fail failing failed failure error erroneous bad) (save saving saved store storing stored))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/03/16 09:49
L6	234	(memory or (self adj test) or BIST).ab. and (((first second) near2 (pass cycle test tester testing tested run))) with (fail failing failed failure error erroneous bad) with (save saving saved store storing stored))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/03/16 09:53
L7	171	(memory or (self adj test) or BIST).ab. and (((first second) near2 (pass cycle test tester testing tested run))) with (fail failing failed failure error erroneous bad) with (save saving saved store storing stored) with (cycle number count content data))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/03/16 09:57
L8	174	(memory or (self adj test) or BIST).ab. and (((first second) near2 (pass cycle test tester testing tested run))) with (fail failing failed failure error erroneous bad) with (save collect saving saved store storing stored) with (cycle number count content data))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/03/16 09:58

## EAST Search History

L9	174	(memory or (self adj test) or BIST).ab. and (((first second) near2 (pass cycle test tester testing tested run)) with (fail failing failed failure error erroneous bad) with (save collect saving gather saved store storing stored) with (cycle number count content data))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/03/16 12:37
L10	1	(09/346268).APP.	USPAT; USOCR	OR	ON	2007/03/16 12:26
L11	69	((memory or (self adj test) or BIST) and (((first second) near2 (pass cycle test tester testing tested run)) with (fail failing failed failure error erroneous bad) with (save collect saving gather saved store storing stored) with (cycle number count content data))))).clm.	US-PGPUB; USPAT	OR	ON	2007/03/16 12:48
S1	50	("5631868" "5668816" "5668947" "5937154" "5956350" "5982681" "6151692" "6012157" "6425103" "6819609" "6874111" "6415394" "6421790" "6625688" "6779141" "6834361" "6424583" "6646937" "6070252" "6249893" "6249889" "4894800" "4974184" "5968192" "6044481" "4918378" "5006787" "5553082" "5764655" "5764878" "5796745" "5818772" "5920515" "5936876" "5954830" "5961653" "5995731" "6018484" "6163862" "6185138" "6233669" "4969148" "5416784" "5422891" "5469443" "5528553" "5513190" "5533032" "5535164" "5563833").pn.	USPAT	OR	ON	2006/07/17 13:35
S2	2	"3783254".pn. "5173906".pn.	USPAT	OR	ON	2005/10/01 19:53
S3	108	("5173906").URPN.	USPAT	OR	ON	2005/10/01 19:54
S4	85	("3783254").URPN.	USPAT	OR	ON	2005/10/01 19:55
S5	238	S1 or S2 or S3 or S4	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/01 19:56
S6	101	S5 and memory.ab.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/01 20:11

## EAST Search History

S7	128	S5 and (memory or (self adj test) or BIST).ab.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/01 20:13
S8	53	(S5 and (memory or (self adj test) or BIST).ab.) and interface	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/03/16 09:34
S9	2782	(test testing tester tested) with (external near3 (\$4RAM memory))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/01 20:33
S10	307	((test testing tester tested) with (external near3 (\$4RAM memory))) same (connect connection interconnect interconnection)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/08 18:54
S11	4	S10 and S5	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/01 20:34
S12	53	((((test testing tester tested) with (external near3 (\$4RAM memory))) same (connect connection interconnect interconnection)) and (BIST or (self adj test)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/14 13:35
S13	2	S12 and S5	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/01 20:36
S14	374	Bayraktaroglu Bayraktaroglu	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/03/16 09:34
S15	83	Bayraktaroglu.in.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/01 20:42
S16	783	Bayraktaroglu.in. or Caty.in. or majumdar.in.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/08 18:54

## EAST Search History

S17	0	S16 and S5	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/01 20:45
S18	9	S16 and S9	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/01 22:25
S19	9	S16 and S9	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/02 13:09
S20	2344	(test testing tested verify verification) near6 ((external outside) near3 (memory RAM DRAM \$4Ram))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/02 13:13
S21	310	((test testing tested verify verification) near6 ((external outside) near3 (memory RAM DRAM \$4Ram))).clm.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/02 13:13
S22	200	((test testing tested verify verification) near6 ((external outside) near3 (memory RAM DRAM \$4Ram))).clm.	USPAT	OR	ON	2005/10/02 13:14
S23	163	((test testing tested verify verification) near4 ((external outside) near3 (memory RAM DRAM \$4Ram))).clm.	USPAT	OR	ON	2005/10/02 13:14
S24	52	((test testing tested verify verification) near4 ((external outside) near3 (memory RAM DRAM \$4Ram))).ab.	USPAT	OR	ON	2005/10/02 13:15
S25	47	((test testing tested verify verification) near4 (external near3 (memory RAM DRAM \$4Ram))).ab.	USPAT	OR	ON	2005/10/02 14:38
S26	15	S23 and S25	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/02 13:17
S27	21	((test testing tested verify verification) near4 (external adj (memory \$4ROM RAM DRAM \$4Ram))).ab.	USPAT	OR	ON	2005/10/02 14:48
S28	40	((test testing tested verify verification) near4 (external adj (memory \$4ROM RAM DRAM \$4Ram))).clm.	USPAT	OR	ON	2006/03/08 18:54

## EAST Search History

S29	33	S28 not S27	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/02 15:32
S30	2	"6067262".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/02 19:24
S31	2	(multiplexer multiplexor) with (instruction adj register) with loop with (test testing)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/02 21:13
S32	2	((multiplexer multiplexor) with (instruction adj register)) same (loop with (test testing))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/14 15:46
S33	2	((multiplexer multiplexor) with (instruction adj register)) same ((loop looping)with (test testing))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/02 21:13
S34	2	((multiplexer multiplexor) with (instruction adj register)) same ((loop looping) with (test testing))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/02 21:13
S35	71	((multiplexer multiplexor) with (register)) same ((loop looping) with (test testing))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/02 21:13
S36	23	(multiplexer multiplexor) with (register) with loop with (test testing)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/08 18:54
S37	48	S35 not S36	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/02 21:33
S38	324	((test testing tester tested) with (external near3 (\$4RAM memory))) same (connect connection interconnect interconnection)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/08 18:54

## EAST Search History

S39	56	((test testing tester tested) with (external near3 (\$4RAM memory))) same (connect connection interconnect interconnection)) and (BIST or (self adj test))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/08 18:54
S40	41	((test testing tested verify verification) near4 (external adj (memory \$4ROM RAM DRAM \$4Ram))).clm.	USPAT	OR	ON	2006/03/08 18:54
S41	812	Bayraktaroglu.in. or Caty.in. or majumdar.in.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/08 18:54
S42	23	(multiplexer multiplexor) with (register) with loop with (test testing)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/08 18:54
S43	8	("5675545" "6088823" "6230290" "6249892" "6760865" "6834361" "6874111" "7020820").pn.	USPAT; EPO; JPO; IBM_TDB	OR	ON	2006/07/14 13:40
S44	2	"20050120284"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/14 16:51
S45	22	US-6557130-\$.DID. OR US-6530052-\$.DID. OR US-6421794-\$.DID. OR US-6357027-\$.DID. OR US-5982681-\$.DID. OR US-5953273-\$.DID. OR US-5751641-\$.DID. OR US-5568437-\$.DID. OR US-5406566-\$.DID. OR US-5173906-\$.DID. OR US-4982380-\$.DID.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/14 16:55
S46	11	US-6557130-\$.DID. OR US-6530052-\$.DID. OR US-6421794-\$.DID. OR US-6357027-\$.DID. OR US-5982681-\$.DID. OR US-5953273-\$.DID. OR US-5751641-\$.DID. OR US-5568437-\$.DID. OR US-5406566-\$.DID. OR US-5173906-\$.DID. OR US-4982380-\$.DID.	USPAT	OR	ON	2006/07/14 17:35
S47	13	S46 "3838260".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/14 17:36
S48	12	S46 "3838260".pn.	USPAT	OR	ON	2006/07/14 18:06

## EAST Search History

S49	2	"20040225912"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/14 18:06
S51	2	"6408413".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/07/17 17:10
S52	1	"1146343"	EPO	OR	ON	2006/07/17 17:10



## Patents

Set Items Description

S1 191 S AU=(OUELLETTE, M? OR OUELLETTE M?)

S2 89 S AU=(ROWLAND, J? OR ROWLAND J?)

S3 266 S S1 OR S2

S4 76 S S3 AND IC=(G06F OR G11C)

S5 58 S S4 AND (MEMORY OR MEMORIES OR RAM OR ROM OR PROM OR OTPROM OR EPROM OR EEPROM OR DRAM OR SDRAM OR VRAM OR CDRAM OR RDRAM OR FRAM OR DIMM OR SODIMM OR ECC OR REGISTER? ?)

S6 58 IDPAT (sorted in duplicate/non-duplicate order)

S7 52 IDPAT (primary/non-duplicate records only)

S8 45 S S7 NOT AY>2003

S9 34 S S5 AND (TEST OR TESTS OR TESTED OR TESTING OR TESTER? ? OR DEBUG?? OR DEBUGGING OR DIAGNOSTIC? ? OR DIAGNOSE? ? OR DIAGNOSING OR DIAGNOSIS)

S10 34 IDPAT (sorted in duplicate/non-duplicate order)

S11 31 IDPAT (primary/non-duplicate records only)

; show files

[File 347] **JAPIO** Dec 1976-2006/Oct(Updated 070201)

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[File 348] **EUROPEAN PATENTS** 1978-2007/ 200708

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[File 349] **PCT FULLTEXT** 1979-2007/UB=20070222UT=20070215

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[File 350] **Derwent WPIX** 1963-2006/UD=200714

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*\*File 350: DWPI has been enhanced to extend content and functionality of the database. For more info, visit <http://www.dialog.com/dwpi/>.*

## Patents - fulltext

Set Items Description

- S1 2603 S BIST OR BUILT(IN)(SYSTEM OR CIRCUIT OR SELF)()TEST
- S2 16311 S (FAIL OR FAILS OR FAILED OR FAILING OR FAILURE? ? OR ERROR? ? OR ERRONEOUS OR FAULT? ? OR FAULTED OR FAULTING OR FLAW OR FLAWS OR FLAWED OR FLAWING OR DEFECT? OR PROBLEM? OR ABNORMAL? OR IRREGULAR? OR TROUBLE? OR BAD ) (5N) CYCLE? ?
- S3 28 S S1 (50N) S2
- S4 2001 S S1 (50N) SELF()TEST? ?
- S5 1316591 S MEMORY OR MEMORIES OR RAM OR ROM OR PROM OR OTPROM OR EPROM OR EEPROM OR DRAM OR SDRAM OR VRAM OR CDRAM OR RDRAM OR FRAM OR DIMM OR SODIMM OR ECC OR REGISTER? ?
- S6 1208907 S TEST OR TESTS OR TESTED OR TESTING OR TESTER? ?
- S7 1230715 S PASS OR PASSES
- S8 2511976 S PHASE? ? OR STAGE? ?
- S9 116291 S (SECOND OR 2ND OR SECONDARY OR ANOTHER OR ADDITIONAL OR OTHER OR NEXT OR FOLLOWING OR FOLLOW? ? OR SUBSEQUENT OR SUCCESSIVE OR SUCCEEDING ) (3W) S6
- S10 53412 S (SECOND OR 2ND OR SECONDARY OR ANOTHER OR ADDITIONAL OR OTHER OR NEXT OR FOLLOWING OR FOLLOW? ? OR SUBSEQUENT OR SUCCESSIVE OR SUCCEEDING ) (3W) S7
- S11 230901 S (SECOND OR 2ND OR SECONDARY OR ANOTHER OR ADDITIONAL OR OTHER OR NEXT OR FOLLOWING OR FOLLOW? ? OR SUBSEQUENT OR SUCCESSIVE OR SUCCEEDING ) (3W) S8
- S12 1394 S S10 (30N) S6
- S13 6178 S S11 (30N) S6
- S14 1250 S S2 (3N) NUMBER? ?
- S15 64 S S2 (3N) (ID OR IDS OR IDENTIFIER? ? OR IDENTIFICATION? ?)
- S16 16 S (S14 OR S15) (5N) (COLLECT??? OR COLLECTION OR GATHER??? OR RETRIEVE? ? OR RETRIEVING OR RETRIEVAL OR FETCH??? OR OBTAIN??? OR GET OR GOT OR GETTING)
- S17 3 S (S14 OR S15) (50N) (S1 OR SELF()TEST? ?)
- S18 383 S (S14 OR S15) (50N) S6
- S19 28 S S18 (50N) S5
- S20 27 S S19 NOT S17
- S21 27 IDPAT (sorted in duplicate/non-duplicate order)
- S22 24 IDPAT (primary/non-duplicate records only)
- S23 333586 S DEBUG?? OR DEBUGGING OR DIAGNOSTIC? ? OR DIAGNOSE? ? OR DIAGNOSING OR DIAGNOSIS
- S24 27603 S (FAIL OR FAILS OR FAILED OR FAILING OR FAILURE? ? OR ERROR? ? OR ERRONEOUS OR FAULT? ? OR FAULTED OR FAULTING OR FLAW OR FLAWS OR FLAWED OR FLAWING OR DEFECT? OR PROBLEM? OR ABNORMAL? OR IRREGULAR? OR TROUBLE? OR BAD ) (10N) CYCLE? ?
- S25 52215 S CYCLE? ? (5N) (NUMBER? ? OR ID OR IDS OR IDENTIFIER? ?)
- S26 2351 S S25 (10N) S24

S27 540 S S26 (50N) (S1 OR S6)  
 S28 55 S S27 (50N) S5  
 S29 35 S S28 NOT S22  
 S30 35 IDPAT (sorted in duplicate/non-duplicate order)  
 S31 34 IDPAT (primary/non-duplicate records only)  
 S32 6 S S26 (50N) (S1 OR SELF()TEST? ?)  
 S33 6 IDPAT (sorted in duplicate/non-duplicate order)  
 S34 4 IDPAT (primary/non-duplicate records only)  
 S35 4 S S34 NOT S22  
 S36 2 S S29 (50N) (S9 OR S12 OR S13)  
 S37 2 S S36 NOT S35  
 S38 30 S S31 NOT (S34 OR S37)  
 S39 20 S S38 AND IC=(G06F OR G11C)  
 S40 51 S S26 (50N) S23  
 S41 12 S S40 (50N) S5  
 S42 10 S S41 NOT (S34 OR S37 OR S39)  
 S43 10 IDPAT (sorted in duplicate/non-duplicate order)  
 S44 7 IDPAT (primary/non-duplicate records only)

; show files

[File 348] **EUROPEAN PATENTS** 1978-2007/ 200708

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[File 349] **PCT FULLTEXT** 1979-2007/UB=20070301UT=20070222

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[File 350] **Derwent WPIX** 1963-2006/UD=200714

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**NPL** - note: no relevant references returned

Set Items Description

S1 15627 S BIST OR BUILT()IN()(SYSTEM OR CIRCUIT OR SELF)()TEST OR SELF()TEST

S2 1193420 S MEMORY OR MEMORIES OR RAM OR ROM OR PROM OR OTPROM OR EPROM OR EEPROM OR DRAM OR SDRAM OR VRAM OR CDRAM OR RDRAM OR FRAM OR DIMM OR SODIMM OR ECC OR REGISTER? ?

S3 9201358 S TEST OR TESTS OR TESTED OR TESTING OR TESTER? ? OR DEBUG?? OR DEBUGGING OR DIAGNOSTIC? ? OR DIAGNOSE? ? OR DIAGNOSING OR DIAGNOSIS

S4 33789 S (FAIL OR FAILS OR FAILED OR FAILING OR FAILURE? ? OR ERROR? ? OR ERRONEOUS OR FAULT? ? OR FAULTED OR FAULTING OR FLAW OR FLAWS OR FLAWED OR FLAWING OR DEFECT? OR PROBLEM? OR ABNORMAL? OR IRREGULAR? OR TROUBLE? OR BAD ) (5N) CYCLE? ?

S5 37862 S CYCLE? ? (3N) ( NUMBER? ? OR ID OR IDS OR IDENTIFIER? ?)

S6 3538 S S5 (10N) S4

S7 0 S S1 AND S2 AND S6

S8 57 S S3 AND S2 AND S6

S9 107 S S6 (5N) (COLLECT??? OR COLLECTION OR GATHER??? OR RETRIEVE? ? OR RETRIEVING OR RETRIEVAL OR FETCH??? OR OBTAIN??? OR GET OR GOT OR GETTING OR ACQUIRE? ? OR ACQUIRING)

S10 0 S S3 AND S2 AND S9

S11 890 S S5 (5N) (COLLECT??? OR COLLECTION OR GATHER??? OR RETRIEVE? ? OR RETRIEVING OR RETRIEVAL OR FETCH??? OR OBTAIN??? OR GET OR GOT OR GETTING OR ACQUIRE? ? OR ACQUIRING)

S12 0 S S3 AND S2 AND S4 AND S11

S13 962 S S4 (5N) (CONTENT? ? OR DATA OR DATASET? ? OR INFORMATION OR INFO)

S14 1 S S8 AND S13

S15 42311 S S2 (10N) (COLLECT??? OR COLLECTION OR GATHER??? OR RETRIEVE? ? OR RETRIEVING OR RETRIEVAL OR FETCH??? OR OBTAIN??? OR GET OR GOT OR GETTING OR ACQUIRE? ? OR ACQUIRING )

S16 0 S S8 AND S15

S17 145232 S (SECOND OR 2ND OR SECONDARY OR ANOTHER OR ADDITIONAL OR OTHER OR NEXT OR FOLLOWING OR FOLLOW? ? OR SUBSEQUENT OR SUCCESSIVE OR SUCCEEDING ) (3W) S3

S18 249231 S (SECOND OR 2ND OR SECONDARY OR ANOTHER OR ADDITIONAL OR OTHER OR NEXT OR FOLLOWING OR FOLLOW? ? OR SUBSEQUENT OR SUCCESSIVE OR SUCCEEDING ) (3W) (PASS OR PASSES OR PHASE? ? OR STAGE? ? OR LOOP? ?)

S19 6949 S S18 (10N) S3

S20 0 S S8 AND (S17 OR S19)

S21 45 S S8 NOT PY>2003

S22 18 RD (unique items)

; show files

[File 8] **Ei Compendex(R)** 1884-2007/Feb W3

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[File 35] **Dissertation Abs Online** 1861-2007/Feb  
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[File 65] **Inside Conferences** 1993-2007/Mar 02  
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[File 2] **INSPEC** 1898-2007/Feb W3  
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[File 94] **JICST-EPlus** 1985-2007/Mar W1  
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*\*File 94: UD200609W2 is the last update for 2006. UD200701W1 is the first update for 2007. The file is complete and up to date.*

[File 111] **TGG Natl.Newspaper Index(SM)** 1979-2007/Feb 27  
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[File 6] **NTIS** 1964-2007/Feb W4  
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[File 434] **SciSearch(R) Cited Ref Sci** 1974-1989/Dec  
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[File 62] **SPIN(R)** 1975-2007/Feb W2  
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[File 56] **Computer and Information Systems Abstracts** 1966-2007/Feb  
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[File 266] **FEDRIP** 2007/Jan  
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## Patents - bib

Set Items Description

S1 576913 S MEMORY OR MEMORIES OR RAM OR ROM OR PROM OR OTPROM OR EPROM OR EEPROM OR DRAM OR SDRAM OR VRAM OR CDRAM OR RDRAM OR FRAM OR DIMM OR SODIMM OR ECC OR REGISTER? ?

S2 308614 S TEST OR TESTS OR TESTED OR TESTING OR TESTER? ? OR DEBUG?? OR DEBUGGING OR DIAGNOSTIC? ? OR DIAGNOSE? ? OR DIAGNOSING OR DIAGNOSIS

S3 4999 S (FAIL OR FAILS OR FAILED OR FAILING OR FAILURE? ? OR ERROR? ? OR ERRONEOUS OR FAULT? ? OR FAULTED OR FAULTING OR FLAW OR FLAWS OR FLAWED OR FLAWING OR DEFECT? OR PROBLEM? OR ABNORMAL? OR IRREGULAR? OR TROUBLE? OR BAD ) (10N) CYCLE? ?

S4 2097 S CYCLE? ? (3N) (NUMBER? ? OR ID OR IDS OR IDENTIFIER? ?)

S5 511 S BIST OR BUILT()IN()(SYSTEM OR CIRCUIT OR SELF)()TEST OR SELF()TEST

S6 88 S S4 (10N) S3

S7 0 S S1 AND S5 AND S6

S8 3 S S1 AND S2 AND S6

; show files

[File 347] JAPIO Dec 1976-2006/Nov(Updated 070228)  
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## NPL

Set Items Description

S1 676 S AU=(OUELLETTE, M? OR OUELLETTE M?)  
S2 1248 S AU=(ROWLAND, J? OR ROWLAND J?)  
S3 137 SELECT AU= "OUELLETTE, M" OR AU= "OUELLETTE, M."  
S4 7 SELECT AU= "OUELLETTE, M R" OR AU= "OUELLETTE, M.R."  
S5 6 SELECT AU= "OUELLETTE, MICHAEL" OR AU= "OUELLETTE, MICHAEL R."  
S6 275 SELECT AU= "OUELLETTE M"  
S7 2 SELECT AU= "OUELLETTE MR"  
S8 1 SELECT AU= "OUELLETTE MICHAEL R"  
S9 428 S S3:S8  
S10 87 SELECT AU= "ROWLAND, J" OR AU= "ROWLAND, J."  
S11 2 SELECT AU= "ROWLAND, J.P."  
S12 0 SELECT AU= "ROWLAND, JEREMY"  
S13 180 SELECT AU= "ROWLAND J"  
S14 4 SELECT AU= "ROWLAND J P"  
S15 7 SELECT AU= "ROWLAND JP"  
S16 280 S S10:S15  
S17 703 S S16 OR S9  
S18 28 S S17 AND (MEMORY OR MEMORIES)  
S19 25 S S18 NOT PY>2003  
S20 11 RD (unique items)  
S21 14019 S (RAM OR ROM OR PROM OR OTPROM OR EPROM OR EEPROM OR DRAM OR SDRAM OR VRAM OR CDRAM OR RDRAM OR FRAM OR DIMM OR SODIMM OR ECC OR REGISTER? ?) (10N) (TEST OR TESTS OR TESTED OR TESTING OR TESTER? ? OR DEBUG?? OR DEBUGGING OR DIAGNOSTIC? ? OR DIAGNOSE? ? OR DIAGNOSING OR DIAGNOSIS)  
S22 3 S S17 AND S21  
S23 1 S S22 NOT S20

; show files

[File 8] **Ei Compendex(R)** 1884-2007/Feb W3  
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[File 35] **Dissertation Abs Online** 1861-2007/Feb  
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*\*File 94: UD200609W2 is the last update for 2006. UD200701W1 is the first update for 2007. The file is complete and up to date.*

[File 111] **TGG Natl.Newspaper Index(SM)** 1979-2007/Feb 26

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*\*File 583: This file is no longer updating as of 12-13-2002.*



# INTERFERENCE SEARCH

## EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	1	((memory or (self adj test) or BIST) and (((first and second) near2 (pass cycle test tester testing tested run)) with (fail failing failed failure error erroneous bad) with (save collect saving gather saved store storing stored) with (cycle number count content data))).clm. and (714/718.ccls. 365/201.ccls.)	US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/03/16 13:15
L2	1	((memory or (self adj test) or BIST) and (((first and second) near2 (pass cycle test tester testing tested run)) with (fail failing failed failure error erroneous bad) with (save collect saving gather saved store storing stored) with (cycle number count content data))).clm. and (714/718.ccls. 365/201.ccls.)	US-PGPUB	OR	ON	2007/03/16 13:15